**TENTATIVE** 

TOSHIBA GATE TURN-OFF THYRISTOR

## S G 3 0 0 0 G X H 2 3 G

**INVERTER APPLICATION** 

Unit in mm

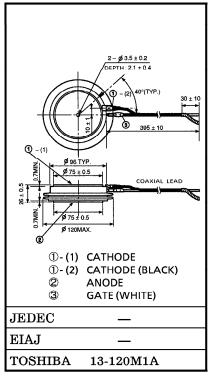
Repetitive Peak Off-State Voltage: VDRM=4500V R.M.S On-State Current  $: I_{T(RMS)} = 1200A$ Peak Turn-Off Current  $: I_{TGQM} = 3000A$ 

Critical Rate of Rise of On-State Current :  $di/dt = 400A/\mu s$ Critical Rate of Rise of Off-State Voltage : dv/dt=1000V/μs

Suitable for 3000V DC Off-State Voltage Application

## **MAXIMUM RATINGS**

CHARACTERISTIC	SYMBOL RATING		UNIT	
Repetitive Peak Off-State Voltage (Note 1)	$v_{ m DRM}$	4500	V	
Repetitive Peak Reverse Voltage	$v_{RRM}$	17	V	
Peak Turn-Off Current (Note 2)	$I_{\text{TGQM}}$	3000	Α	
R.M.S On-State Current (Note 3)	I <sub>T</sub> (RMS)	1200	Α	
Peak One Cycle Surge On-State Current (Non Repetitive, 10ms- Width Half Sine Waveform)	$I_{TSM}$	19000	A	
Critical Rate of Rise of On-State Current (Note 4)	di/dt	400	A/μs	
Peak Forward Gate Current	$I_{\text{FGM}}$	100	Α	
Average Forward Gate Power Dissipation	P <sub>FG</sub> (AV)	50	W	
Average Reverse Gate Power Dissipation	P <sub>RG</sub> (AV)	150	w	
R.M.S Gate Current (Note 5)	I <sub>G (RMS)</sub>	42	Α	
Peak Reverse Gate Voltage (at Static)	$v_{RGM}$	17	V	
Operating Junction Temperature Range	$T_{j}$	-40~125	°C	
Storage Temperature Range	$\mathrm{T_{stg}}$	-40~150	°C	
Mounting Force	_	28.5~44.0	kN	



Weight: 1500g

Note 1:  $V_{GK} = -2V$ 

Note 2 :  $V_{DM} = 4500V$ ,  $C_S \ge 3\mu F$ ,  $R_S = 5\Omega$ ,  $di_{GQ}/dt = 50A/\mu s$ ,  $V_{DSP} \le 850V$ ,

L<sub>S</sub>=200nH (Stray inductance of snubber [GTO-C<sub>S</sub>-D<sub>S</sub>] loop)

Note 3: 50Hz Half Sine Waveform at Tf=76°C

Note 4:  $V_D = 3000V$ ,  $I_{GM} \ge 25A$ 

Note 5: Ambient Temperature of coaxial Gate-Cathode lead=90°C

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## **ELECTRICAL CHARACTERISTICS**

CHARACTERISTIC	SYMBOL	TEST CONDITION		MIN.	TYP.	MAX.	UNIT
Repetitive Peak Off-State Current	$I_{ m DRM}$	$V_{DRM} = 4500V, V_{GK} = -2V,$ $T_i = 125$ °C		_	_	100	mA
Repetitive Peak Reverse Current	$I_{RRM}$	$V_{RRM} = 17V, T_j = 125$ °C		_	_	10	mA
Repetitive Peak Reverse Gate Current	$I_{ m RGM}$	$V_{RGM} = 17V, T_j = 125^{\circ}C$		_	_	10	mA
Peak On-State Voltage	$V_{TM}$	$I_{TM} = 3000A, T_j = 125^{\circ}C$		_	_	4.0	V
Gate Trigger Voltage	$v_{GT}$	$V_D = 24V,$ $R_L = 0.1\Omega$	$T_j = -40$ °C			_	V
			$T_j = 25$ °C		—	1.5	·
Gate Trigger Current	$I_{GT}$		$T_{\hat{j}} = -40^{\circ}C$	_		<u> </u>	A
			$T_j = 25$ °C	_		1.8	A
Turn-On Delay Time	$t_{ m d}$	$V_{ m D}\!=\!3000{ m V},~{ m di}/{ m dt}\!=\!400{ m A}/\mu{ m s}, \ I_{ m TM}\!=\!3000{ m A},~I_{ m GM}\!=\!25{ m A}, \ T_{ m j}\!=\!25^{\circ}{ m C}$		_	_	3	μs
Turn-On Time	$t_{\mathrm{gt}}$			_	_	10	$\mu$ s
Critical Rate of Rise of Off-	dv / dt		000V, $V_{GK} = -2V$ , ential Rise, $T_j = 125$ °C		_	_	V/μs
State Voltage		Exponential Rise,					
Storage Time	$t_{\mathrm{S}}$	$ I_{TGQ}  = 3000 \text{A}, V_{DM} = 4500 \text{V},$		_		30	$\mu$ s
Gate Turn-Off Time	${ m t_{gq}}$	$C_S = 6\mu F$ , $V_D \le 3000 V$ , $R_S = 5\Omega$ ,			—	33	$\mu$ s
Tail Time	t <sub>tail</sub>	$\int \! \mathrm{diGQ} /  \mathrm{dt} \! = \! 50 \mathrm{A} /  \mu \mathrm{s},$				115	$\mu$ s
Gate Turn-Off Current	$I_{\mathbf{GQ}}$	$T_j = 125$ °C, $V_{DSP} \le 850$ V				770	Α
Thermal Resistance	$R_{ ext{th (j-f)}}$	(Junction to Fin)		_	_	0.014	°C/W

(Note) The switching loss value is different from SG3000GXH29.  $E_{\mbox{OFF}}$  is about 0.7 times as SG3000GXH29.  $E_{\mbox{ON}}$  is same as SG3000GXH29.